

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,307	KER ET AL.	
Examiner	Art Unit	
Tsz K. Chiu	2822	

SEARCHED						
Class	Subclass	Date	Examiner			
257	119-120, 339,341,3 55- 356,373	3/30/06	тс			
257	401	3/30/2006	TC			
257	492-494	3/20/2006	TC			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
257	492	3/30/2006	тс	
EAST (text search see attach)		3/30/2006	тс	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Discussed with Primary examiner David Coleman	3/30/2006	тс		
EAST (text search see attach)	3/30/2006	тс		
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